

## 54LCX16373

# Low Voltage 16-Bit Transparent Latch with 5V Tolerant Inputs and Outputs

### General Description

The LCX16373 contains sixteen non-inverting latches with TRI-STATE® outputs and is intended for bus oriented applications. The device is byte controlled. The flip-flops appear transparent to the data when the Latch Enable (LE) is HIGH. When LE is low, the data that meets the setup time is latched. Data appears on the bus when the Output Enable ( $\overline{OE}$ ) is LOW. When OE is HIGH, the outputs are in TRI-STATE.

The LCX16373 is designed for low voltage (3.3V)  $V_{CC}$  applications with capability of interfacing to a 5V signal environment.

The LCX16373 is fabricated with an advanced CMOS technology to achieve high speed operation while maintaining CMOS low power dissipation.

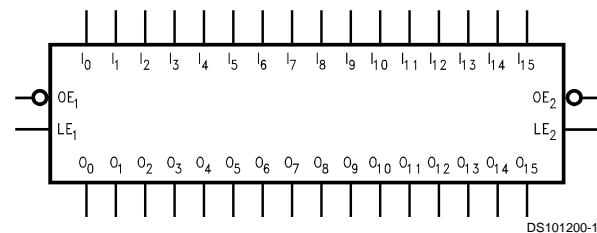
### Features

- 5V tolerant inputs and outputs
- Power down high impedance inputs and outputs
- Supports live insertion/withdrawal
- 2.0V–3.6V  $V_{CC}$  supply operation
- $\pm 24$  mA output drive
- Implements patented noise/EMI reduction circuitry
- Functionally compatible with the 54 series 16373
- ESD performance:
  - Human body model > 2000V
  - Machine model > 200V
- Standard Microcircuit Drawing (SMD) 5962-9953401

### Ordering Code

Order Number	Package Number	Package Description
54LCX16373W-QML	WA48A	48-Lead Ceramic Flatpack

### Logic Symbol

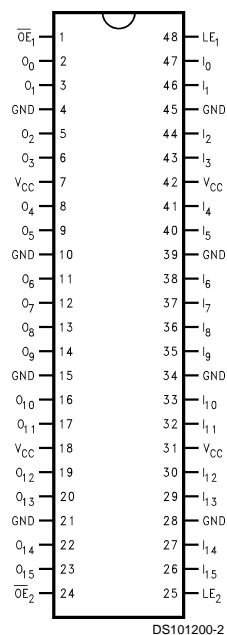


### Pin Descriptions

Pin Names	Description
$\overline{OE}_n$	Output Enable Input (Active Low)
$LE_n$	Latch Enable Input
$I_0$ – $I_{15}$	Inputs
$O_0$ – $O_{15}$	Outputs

### Connection Diagram

#### Pin Assignment for Cerpack



## Functional Description

The LCX16373 contains sixteen D-type latches with TRI-STATE standard outputs. The device is byte controlled with each byte functioning identically, but independent of the other. Control pins can be shorted together to obtain full 16-bit operation. The following description applies to each byte. When the Latch Enable ( $LE_n$ ) input is HIGH, data on the  $I_n$  enters the latches. In this condition the latches are transparent, i.e. a latch output will change state each time its I input changes. When  $LE_n$  is LOW, the latches store information that was present on the I inputs a setup time preceding the HIGH-to-LOW transition of  $LE_n$ . The TRI-STATE standard outputs are controlled by the Output Enable ( $\overline{OE}_n$ ) input. When  $\overline{OE}_n$  is LOW, the standard outputs are in the 2-state mode. When  $\overline{OE}_n$  is HIGH, the standard outputs are in the high impedance mode but this does not interfere with entering new data into the latches.

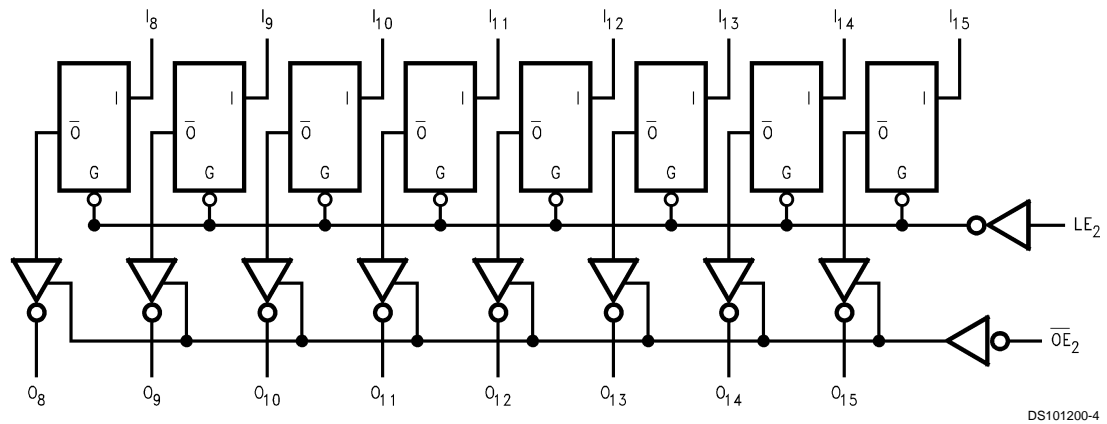
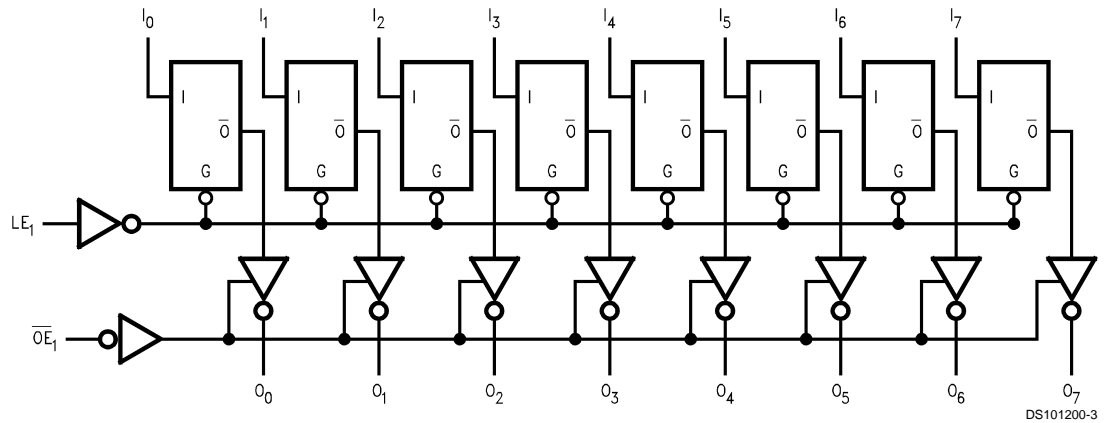
Inputs			Outputs
$LE_1$	$\overline{OE}_1$	$I_0-I_7$	$O_0-O_7$
X	H	X	Z
H	L	L	L
H	L	H	H
L	L	X	$O_0$

Inputs			Outputs
$LE_2$	$\overline{OE}_2$	$I_8-I_{15}$	$O_8-O_{15}$
X	H	X	Z
H	L	L	L
H	L	H	H
L	L	X	$O_0$

H = High Voltage Level  
 L = Low Voltage Level  
 X = Immaterial  
 Z = High Impedance  
 $O_0$  = Previous  $O_0$  before HIGH to LOW transition of Latch Enable

## Logic Diagrams



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

**Absolute Maximum Ratings** (Note 1)

Supply Voltage ( $V_{CC}$ )	-0.5V to +7.0V
DC Input Voltage ( $V_I$ )	-0.5V to +7.0V
DC Input Diode Current ( $I_{IK}$ )	
$V_I < \text{GND}$	-50 mA
DC Output Diode Current ( $I_{OK}$ )	
$V_O < \text{GND}$	-50mA
$V_O \geq V_{CC}$	+50mA
DC Output Voltage ( $V_O$ ) (Note 2)	
Output in High or Low State	-0.5V to $V_{CC} + 0.5V$
Output in TRI-STATE	-0.5V to 7.0V
DC Output Source or Sink Current ( $I_O$ )	$\pm 50\text{mA}$
DC $V_{CC}$ or Ground Current	$\pm 400\text{mA}$
Storage Temperature Range ( $T_{STG}$ )	-65°C to +150°C
Power Dissipation	750mW
Junction Temperature ( $T_J$ )	175°C

**Recommended Operating Conditions** (Note 3)

Supply Voltage ( $V_{CC}$ )	
Operating	2.7V to 3.6V
Data Retention	1.5V to 3.6V
Input Voltage ( $V_I$ )	0V to 5.5V
Output Voltage ( $V_O$ )	
High or Low State	0V to $V_{CC}$
TRI-STATE	0V to 5.5V
Operating Temperature ( $T_A$ )	-55°C to +125°C
Minimum Input Edge Rate ( $\Delta t/\Delta V$ )	
$V_{IN}$ from 0.8V to 2.0V, $V_{CC} = 3.0V$	0ns/V to 10ns/V

**Note 1:** The Absolute Maximum Ratings are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the Absolute Maximum Ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

**Note 2:**  $I_O$  Absolute Maximum Rating must be observed.

**Note 3:** Unused inputs must be held HIGH or LOW. They may not float.

**DC Electrical Characteristics**

Symbol	Parameter	Conditions	$V_{CC}$ (V)	$T_A = -55^\circ\text{C to } +125^\circ\text{C}$		Units
				Min	Max	
$V_{IH}$	HIGH Level Input Voltage		2.7–3.6	2.0		V
$V_{IL}$	LOW Level Input Voltage		2.7–3.6		0.8	V
$V_{OH}$	HIGH Level Output Voltage	$I_{OH} = -100 \mu\text{A}$	2.7–3.6	$V_{CC} - 0.2$		V
		$I_{OH} = -12 \text{ mA}$	2.7	2.2		V
		$I_{OH} = -12 \text{ mA}$	3.0	2.4		V
		$I_{OH} = -24 \text{ mA}$	3.0	2.2		V
$V_{OL}$	LOW Level Output Voltage	$I_{OL} = 100 \mu\text{A}$	2.7–3.6		0.2	V
		$I_{OL} = 12 \text{ mA}$	2.7		0.4	V
		$I_{OL} = 24 \text{ mA}$	3.0		0.55	V
$I_I$	Input Leakage Current	$0 \leq V_I \leq 5.5V$	2.7–3.6		$\pm 5.0$	$\mu\text{A}$
$I_{OZ}$	TRI-STATE Output Leakage	$0 \leq V_O \leq 5.5V$ $V_I = V_{IH}$ or $V_{IL}$	2.7–3.6		$\pm 5.0$	$\mu\text{A}$
$I_{OFF}$	Power-Off Leakage Current	$V_I$ or $V_O = 5.5V$	0		10	$\mu\text{A}$
$I_{CC}$	Quiescent Supply Current	$V_I = V_{CC}$ or GND	2.7–3.6		20	$\mu\text{A}$
		$3.6V \leq V_I, V_O \leq 5.5V$	2.7–3.6		$\pm 20$	$\mu\text{A}$
$\Delta I_{CC}$	Increase in $I_{CC}$ per Input	$V_{IH} = V_{CC} - 0.6V$	2.7–3.6		500	$\mu\text{A}$

## AC Electrical Characteristics

Symbol	Parameter	$T_A = -55^\circ\text{C to } +125^\circ\text{C}, C_L = 50\text{pF}, R_L = 500\Omega$				Units
		$V_{CC} = 3.3\text{V} \pm 0.3\text{V}$		$V_{CC} = 2.7\text{V}$		
		Min	Max	Min	Max	
$t_{PHL}$	Propagation Delay	1.0	6.0	1.5	6.5	ns
$t_{PLH}$	$I_n$ to $O_n$	1.0	6.0	1.5	6.5	
$t_{PHL}$	Propagation Delay	1.0	6.5	1.5	7.0	ns
$t_{PLH}$	LE to $O_n$	1.0	6.5	1.5	7.0	
$t_{PZL}$	Output Enable Time	1.0	6.5	1.5	7.0	ns
$t_{PZH}$		1.0	6.5	1.5	7.0	
$t_{PLZ}$	Output Disable Time	1.0	6.5	1.5	7.0	ns
$t_{PHZ}$		1.0	6.5	1.5	7.0	
$t_S$	Setup Time, $I_n$ to LE	2.5		2.5		ns
$t_H$	Hold Time, $I_n$ to LE	2.0		2.0		ns
$t_W$	LE Pulse Width	3.5		3.5		ns
$t_{OSHL}$	Output to Output Skew (Note 4)		1.0		1.0	ns
$t_{OSLH}$			1.0		1.0	

**Note 4:** Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH to LOW ( $t_{OSHL}$ ) or LOW to HIGH ( $t_{OSLH}$ ). Parameter guaranteed by design.

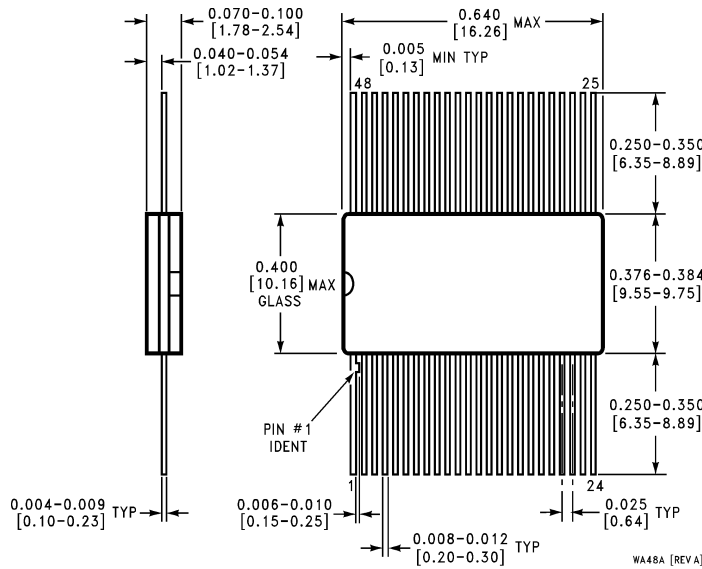
## Dynamic Switching Characteristics

Symbol	Parameter	Conditions	$V_{CC}$ (V)	$T_A = 25^\circ\text{C}$	Units
				Max	
$V_{OLP}$	Quiet Output Dynamic Peak $V_{OL}$	$C_L = 50\text{ pF}, V_{IH} = 3.3\text{V}, V_{IL} = 0\text{V}$	3.3	1.2	V
$V_{OLV}$	Quiet Output Dynamic Valley $V_{OL}$	$C_L = 50\text{ pF}, V_{IH} = 3.3\text{V}, V_{IL} = 0\text{V}$	3.3	-1.1	V

## Capacitance

Symbol	Parameter	Conditions	Max	Units
$C_{IN}$	Input Capacitance	$V_{CC} = \text{Open}, V_I = 0\text{V or } V_{CC}$	10	pF
$C_{OUT}$	Output Capacitance	$V_{CC} = 3.3\text{V}, V_I = 0\text{V or } V_{CC}$	12	pF
$C_{PD}$	Power Dissipation Capacitance	$V_{CC} = 3.3\text{V}, V_I = 0\text{V or } V_{CC}, f = 10\text{ MHz}$	40	pF

**Physical Dimensions** inches (millimeters) unless otherwise noted



**48-Lead Ceramic Flatpack  
Package Number WA48A**

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